## Angular Dispersion with BT Gamma data

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## Configurations

- Normal incidence
  - Tower 2: all gamma runs (both full brems. and tagged) have been used at 0°. The pion contamination has been rejected by requiring the X Vertex position in Tower 2 (VtxX < 350.)</li>
  - Tower 3: all gamma runs (both full brems. and tagged) have been used at 0°
- 30°: all gamma runs (both full brems. and tagged) have been used at 30°
- 50°: all gamma runs (both full brems. and tagged) have been used at 50°
- MC at normal incidence on Tower 3

### **Total Triggers Vs. Run**



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### **Event classification**

### Score

- Class A: events with 1 vertex
  - Class A.1: events with 2 tracks
    - Class A.1.1: CalCsIRLn > 6 New
  - Class A.2: events with 1 track
    - Class A.2.1: CalCsIRLn > 6 New
- Class B: events with 2 Vertices
- Class C: events with 3 o more Vertices

The CU has been used as standalone detector Level 0 Cut: CalEnergyRaw > 0

### **Total Radiation Length in crystals**



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### **Energy calibration - Class A events**



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### **Energy bias – Class A events**



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### X Vertex position



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### **Y Vertex position**



### **Z Vertex position**



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### **Energy distribution**



### **Angular dispersion evaluation**

- The gamma angle has been calculated with the respect the nominal beam direction
  - Beam direction: (-Sin(theta), 0, -Cos(theta))
    where theta is the tilted angle of the CU
  - Measured direction: Vertex direction in the root files
- For each bin energy, the angular dispersion distribution is filled in a histogram with 0.1° bin width

### Angular distribution, 79.6 < E(MeV) < 126.2

#### Tower 2 - Real Data at Normal Incidence



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### **PSF evaluation**

- At given fraction, *f*, (e.g. 68% or 95%), the angular bin number *i* is found such that the integral of events, *P<sub>i</sub>*, is *P<sub>i</sub> < fN < P<sub>i+1</sub>*, where N is the total number of entries.
- The angle,  $\theta_f$ , at the fraction f is evaluated as  $\theta_f = \theta_i + h (fN P_i)/(P_{i+1} P_i)$ , where h is the angular bin step (0.1°)
- The statistical error  $\delta \theta_f$  has been evaluated by taking only the error (Poisson) for the number counts *N*, *P*<sub>i</sub> and *P*<sub>i+1</sub>, i.e.  $\delta \theta_i = 0$  and  $\delta h = 0$

### **Systematic errors**

- Beam divergence: few mrad,  $\delta \theta_f \sim 0.1^\circ$
- CU position with respect to the beam:  $\delta \theta_f \sim 0.1^{\circ}$ 
  - We have studied the angular distribution in the few electron runs taken just before/after the photon runs with B off.
- Gamma production angle by bremsstrahlung with respect to the electron: few mrad,  $\delta \theta_f \sim 0.1^\circ$

The quoted value comes from the cross section used in Geant code

### **PSF at 68% - Class A.1.1**



Tower 3 - Angular Resolution Vs. Reconstructed Energy at Normal Incidence



### **PSF at 95% - Class A.1.1.**

Tower 2 - Angular Resolution Vs. Reconstructed Energy at Normal Incidence

Tower 3 - Angular Resolution Vs. Reconstructed Energy at Normal Incidence



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## PSF 95% to 68% ratio – Class A.1.1

Tower 3 - Angular Resolution Vs. Reconstructed Energy at Normal Incidence 5 5 Class A.1.1 with systematic erro 4.5Class A.1.1 with systematic error 4.5 Class A.1.1 Thin with systematic error Class A.1.1 Thin with systematic error 4 Class A.1.1 Tkick with systematic error Δ Class A 1 1 Tkick with systematic erro 3 2 0.5 0.5 0 0  $10^{3}$ 10<sup>2</sup> 10<sup>2</sup> 10<sup>3</sup> Energy (MeV) Energy (MeV) Angular Resolution Vs. Reconstructed Energy at 30 Deg Incidence Angular Resolution Vs. Reconstructed Energy at 50 Deg Incidence 5 5 Class A.1.1 with systematic error 4.5 Class A.1.1 with systematic error 4.5 Class A.1.1 Thin with systematic error Class A.1.1 Thin with systematic error Δ Δ Class A 1 1 Tkick with systematic erro Class A.1.1 Tkick with systematic error ມູ ເຊັ່ງ .5 1⊦ 0.5 0.5 0 0  $10^{2}$ 10<sup>3</sup> 10<sup>2</sup> 10<sup>3</sup> Energy (MeV) Energy (MeV)

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### **PSF at 68% - Class A.2.1**



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### MC normal incidence Tower 3



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### **Data-MC comparison: PSF 68%**



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## Data-MC comparison: PSF 68% in Thick and Thin layers



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### **Data-MC comparison: PSF 95%**



### Data-MC comparison: PSF 95% in Thick and Thin layers



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### Data-MC comparison: PSF 95% to 68% Ratio



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### Conclusion

- The angular dispersion has been evaluated at normal incidence in Tower 2 and 3, at 30° and at 50°
  - All available photon runs (both full brems and tagged) have been merged
- The data are quite in agreement with the MC, at least at normal incidence